

# MT4953A

## P-Channel Enhancement Mode Field Effect Transistor

### Product Summary

- $V_{DS} = -20V$
- $I_D = -5A$
- $R_{DS(ON)} \leq 65m\Omega$   
@  $V_{GS} = -10V/-4.9A$
- $R_{DS(ON)} \leq 84m\Omega$   
@  $V_{GS} = -4.5V/-3.6A$

### Features

- Advanced Trench Process Technology.
- High Density Cell Design for Ultra Low
- On-Resistance.
- Lead free product is acquired.
- RoHS Compliant.

### Applications :

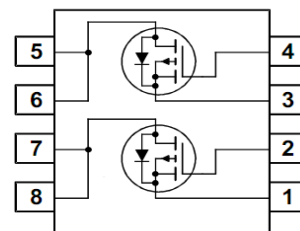
- Load Switch.
- PWM Applications.



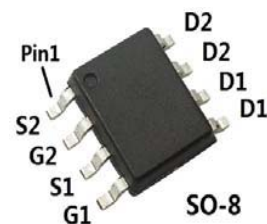
**MT Semiconductor®**

<http://www.mtsemi.com>

### Simplified Schematic



### MARKING DIAGRAM & PIN ASSIGNMENT



### Absolute Maximum Ratings ( $T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Steady State	Units
$V_{DS}$	Drain-Source Voltage	-20	V
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V
$I_D$	Continuous Drain Current <sup>1</sup>	-5	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	-27	A
$I_S$	Continuous Source Current (Diode Conduction) <sup>1</sup>	-2	A
$P_D$	Maximum Power Dissipation <sup>1</sup>	1.8	W
$T_J, T_{STG}$	Operating Junction and Storage Temperature Range	-55~150	$^\circ C$

Notes:

1. Surface Mounted on 1" x 1" FR4 Board,  $t \leq 10$  Sec.
2. Pulse width limited by maximum junction temperature.

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
MT4953A	MT4953A	SO-8	-	-	2500

## Thermal Resistance Ratings

Symbol	Parameter		Typical	Maximum	Unit
R <sub>thJA</sub>	Maximum Junction-to-Ambient	t ≤ 10 Sec	45	69	°C/W
		Steady State	85	104	
R <sub>thJF</sub>	Maximum Junction-to-Foot (Drain)	Steady State	37	46	

## Electrical Characteristics (T<sub>A</sub>=25°C, unless otherwise noted)

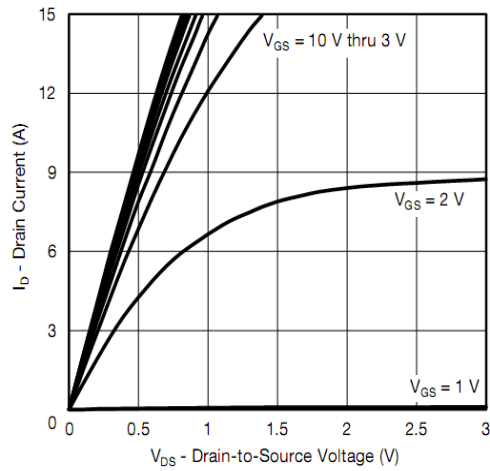
Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
<b>• Static Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-20	-	-	V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-0.7	-1.1	-1.2	V
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±12V	-	-	±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V	-	-	-1	μA
		V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 85°C	-	-	-30	
R <sub>DS(on)</sub>	Drain Source On State Resistance <sup>a</sup>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -4.9A	-	60	65	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3.6A	-	75	84	
g <sub>fs</sub>	Forward Transconductance <sup>a</sup>	V <sub>DS</sub> = -5V, I <sub>D</sub> = -4A	-	16	-	S
V <sub>SD</sub>	Diode Forward Voltage <sup>a</sup>	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1A	-	-0.8	-1.2	V
<b>• Dynamic Characteristics <sup>b</sup></b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> = 0V, f = 1MHz	-	1360	-	pF
C <sub>oss</sub>	Output Capacitance		-	240	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	170	-	
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -15V, V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	-	14	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	2.6	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	5.2	-	
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = -15V, R <sub>L</sub> = 3Ω I <sub>D</sub> = -1.0A, V <sub>GEN</sub> = -10V, R <sub>G</sub> = 6Ω	-	17	-	nSec
t <sub>r</sub>	Rise Time		-	14	-	
T <sub>d(off)</sub>	Turn-Off Delay Time		-	65	-	
t <sub>f</sub>	Fall Time		-	29	-	
R <sub>g</sub>	Gate Resistance	V <sub>GS</sub> = 0, V <sub>DS</sub> = 0, f = 1MHz	-	8	-	Ω
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> = -4A, di/dt = 100A/μs	-	25	-	nSec
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	10	-	nC

Note:

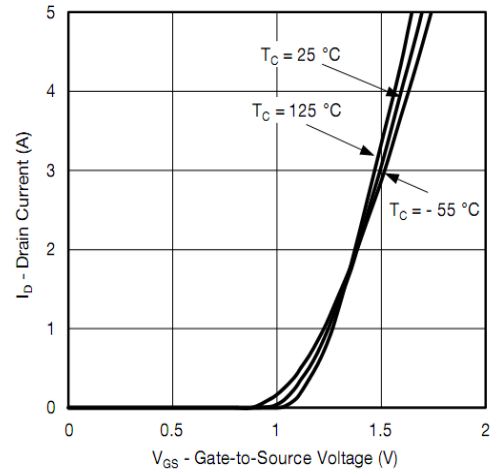
a. Pulse test; pulse width ≤ 300μs, duty cycle ≤ 2%.

b. Guaranteed by design, not subject to production testing.

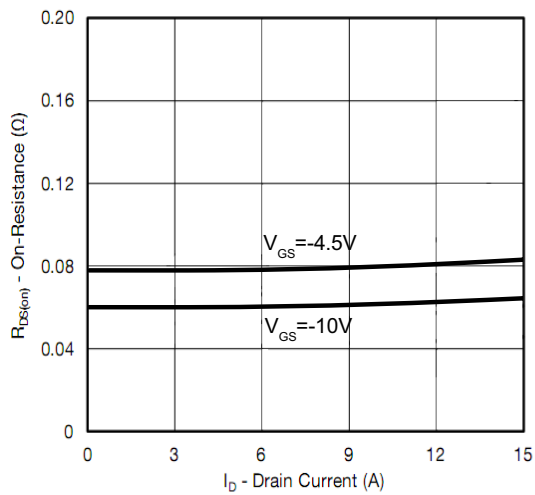
## Characteristics Curve



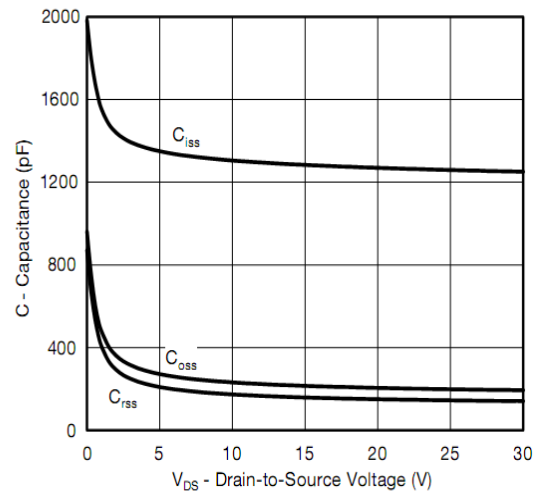
Output Characteristics



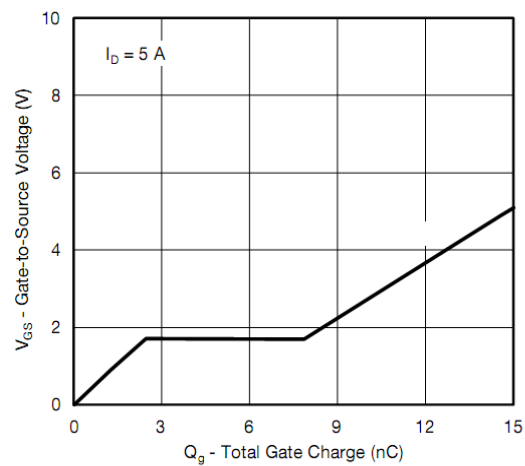
Transfer Characteristics



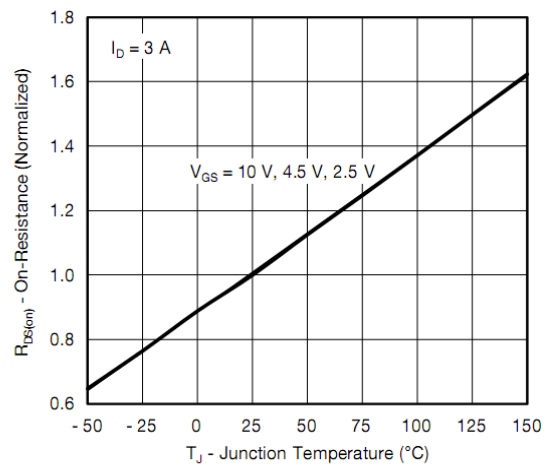
On-Resistance vs. Drain Current and Gate Voltage



Capacitance

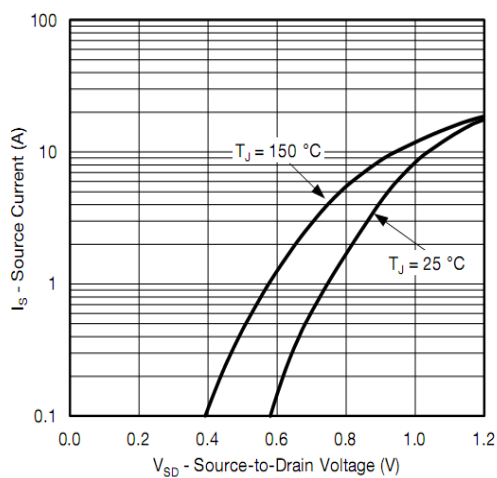


Gate Charge

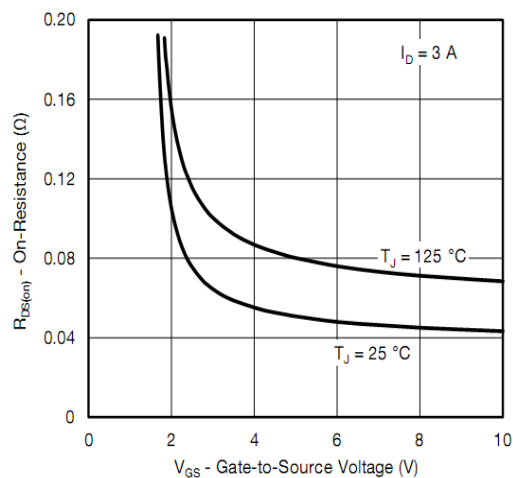


On-Resistance vs. Junction Temperature

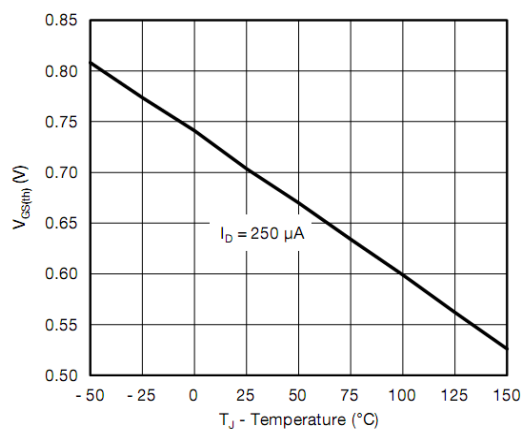
## Characteristics Curve



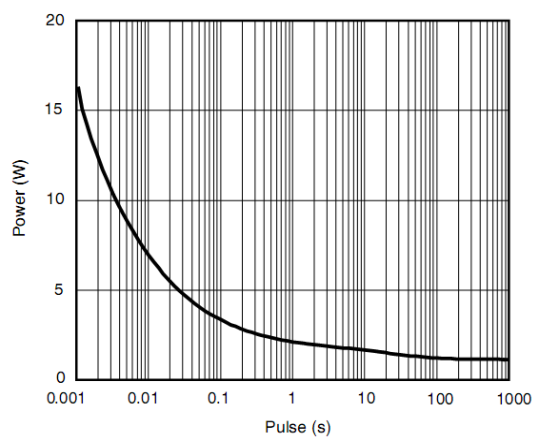
Source-Drain Diode Forward Voltage



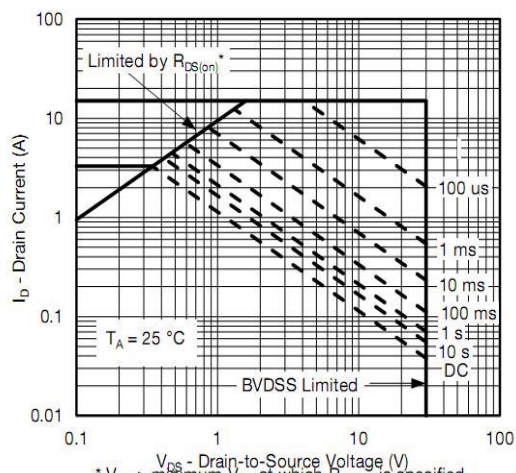
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

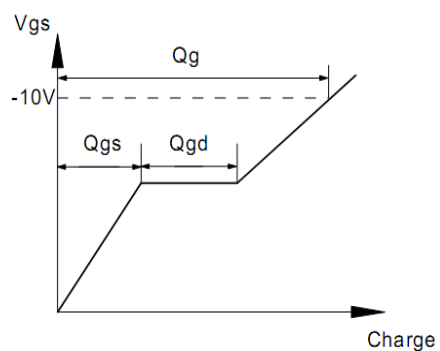
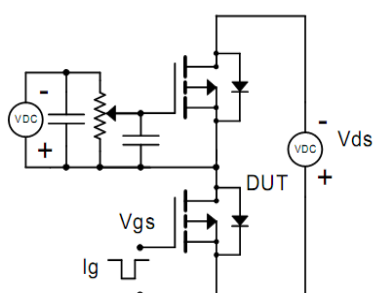


Single Pulse Power, Junction-to-Ambient



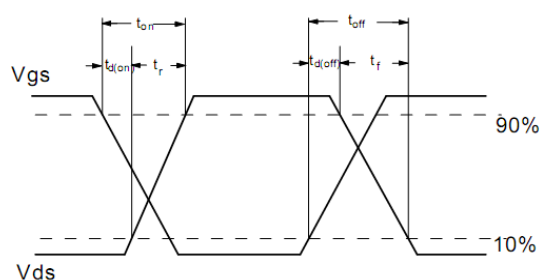
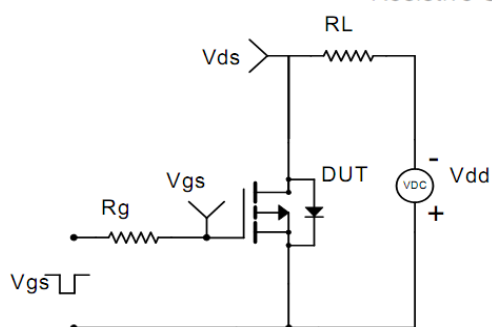
Safe Operating Area, Junction-to-Ambient

Gate Charge Test Circuit &amp; Waveform

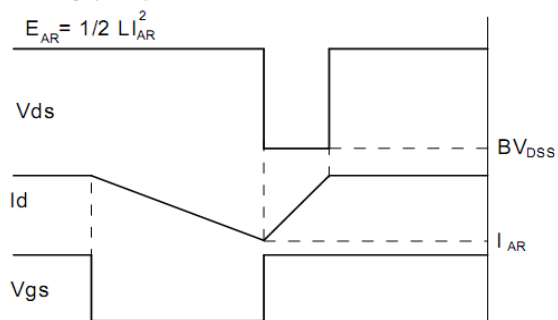
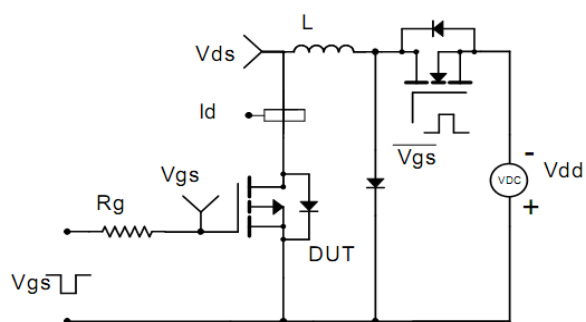


Resistive Switching Test Circuit &amp; Waveforms

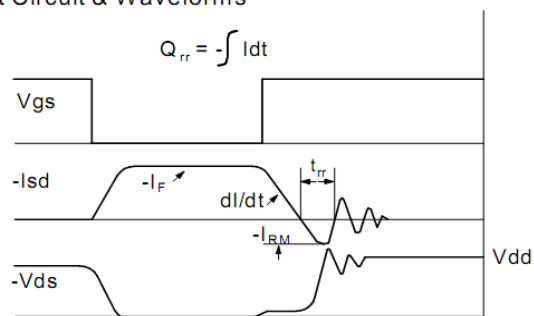
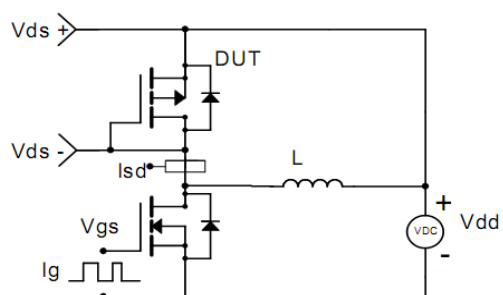
Resistive Switching Test Circuit &amp; Waveforms



Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms

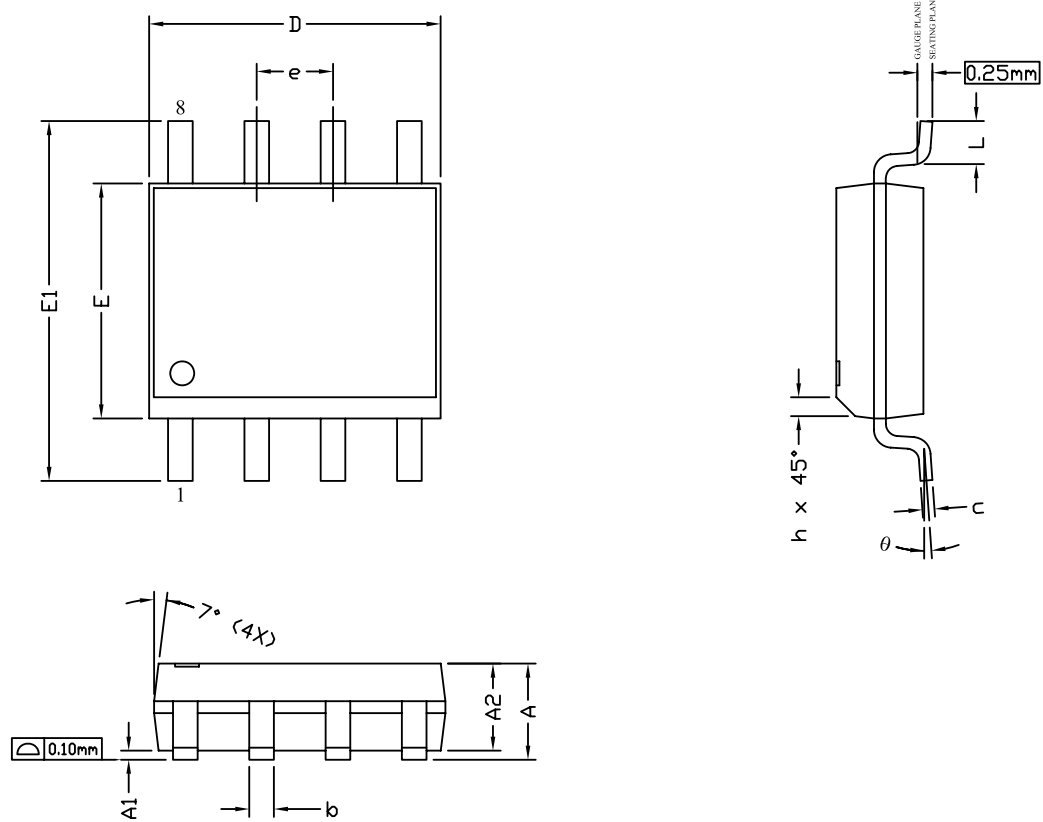


Diode Recovery Test Circuit &amp; Waveforms

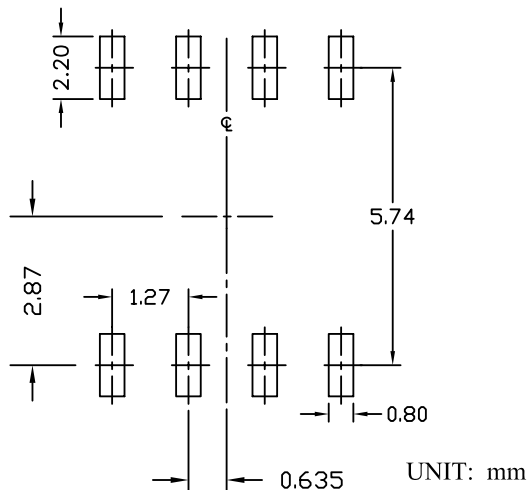


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Version	rev H

## S08 PACKAGE OUTLINE



## RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.35	1.65	1.75	0.053	0.065	0.069
A1	0.10	—	0.25	0.004	—	0.010
A2	1.25	1.50	1.65	0.049	0.059	0.065
b	0.31	—	0.51	0.012	—	0.020
c	0.17	—	0.25	0.007	—	0.010
D	4.80	4.90	5.00	0.189	0.193	0.197
E	3.80	3.90	4.00	0.150	0.154	0.157
e	1.27 BSC			0.050 BSC		
E1	5.80	6.00	6.20	0.228	0.236	0.244
h	0.25	—	0.50	0.010	—	0.020
L	0.40	—	1.27	0.016	—	0.050
$\theta$	$0^\circ$	—	$8^\circ$	$0^\circ$	—	$8^\circ$

### NOTE

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. DIMENSIONS ARE INCLUSIVE OF PLATING.
3. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
4. DIMENSION L IS MEASURED IN GAUGE PLANE.
5. CONTROLLING DIMENSION IS MILLIMETER.  
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

## Part Marking Information

### SO-8 (PMG Code )

SO-8 Devices



MT4953A = Example Base Part Number

● = Pin 1 Indicator

△ = ESD Symbol (⚡)

9 = Year Code

A = Month Code

3 = Week Code

H = Assembly Factory Code

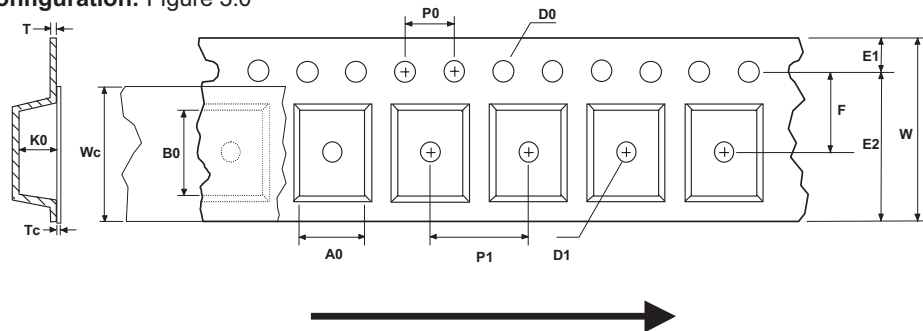
**NOTE:**

1. For analog switches base part includes DG prefix. Package suffix may or may not be present, depending on room available.

The current marking strategy is reflected. Contact your local sales representative for historical marking strategies for these packages.

## SO-8 Tape and Reel Data, continued

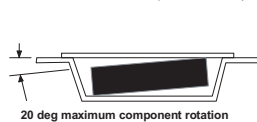
### SO(8lds) Embossed Carrier Tape Configuration: Figure 3.0



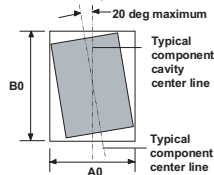
Dimensions are in millimeter

Pkg type	A0	B0	W	D0	D1	E1	E2	F	P1	P0	K0	T	Wc	Tc
SOIC(8lds) (12mm)	6.50 +/-0.10	5.30 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.60 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	2.1 +/-0.10	0.450 +/- 0.150	9.2 +/-0.3	0.06 +/-0.02

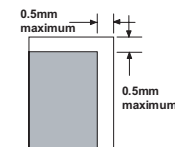
Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)  
Component Rotation

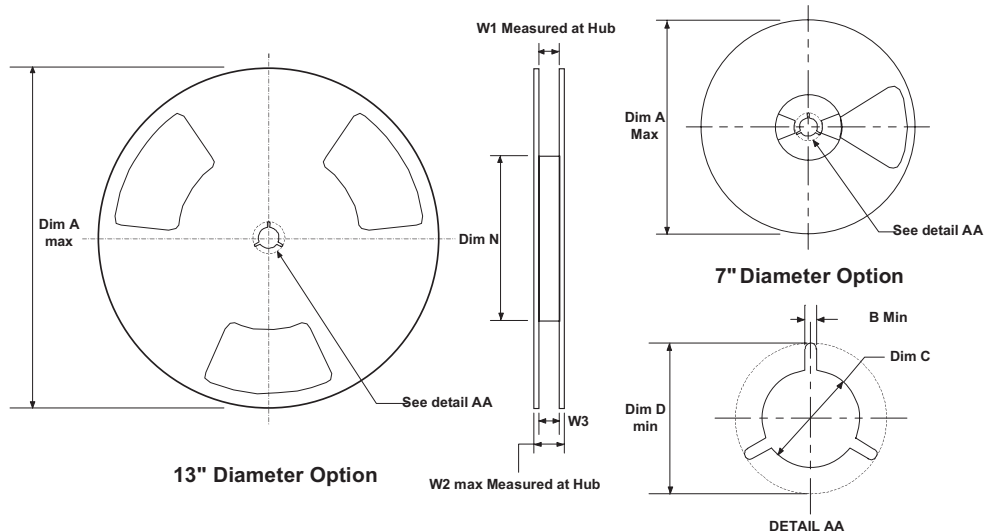


Sketch B (Top View)  
Component Rotation



Sketch C (Top View)  
Component lateral movement

### SOIC(8lds) Reel Configuration: Figure 4.0



Dimensions are in inches and millimeters

Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512+0.020/-0.008 13+0.5/-0.2	0.795 20.2	2.165 55	0.488+0.078/-0.000 12.4+2/0	0.724 18.4	0.469-0.606 11.9-15.4
12mm	13" Dia	13.00 330	0.059 1.5	512+0.020/-0.008 13+0.5/-0.2	0.795 20.2	7.00 178	0.488+0.078/-0.000 12.4+2/0	0.724 18.4	0.469-0.606 11.9-15.4



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10. 本公司一直致力于提高产品的质量和可靠性, 但一般来说, 半导体产品总会以一定的概率发生故障、或者由于使用条件不同而出现错误运行等。为了避免因本公司的产品发生故障或者错误运行而导致人身事故和火灾或造成社会性的损失, 希望客户能自行负责进行冗余设计、采取延烧对策及进行防止错误运行等的安全设计(包括硬件和软件两方面的设计)以及老化处理等, 这是作为机器和系统的出厂保证。特别是单片机的软件, 由于单独进行验证很困难, 所以要求在顾客制造的最终的机器及系统上进行安全检验工作。
11. 如果把本资料所记载的产品从其载体设备上卸下, 有可能造成婴儿误吞的危险。顾客在将本公司产品安装到顾客的设备上时, 请顾客自行负责将本公司产品设置为不容易剥落的安全设计。如果从顾客的设备上剥落而造成事故时, 本公司将不承担任何责任。
12. 在未得到本公司的事先书面认可时, 不可将本资料的一部分或者全部转载或者复制。
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### Keep safety first in your circuit designs!

1. MOS-TECH Semiconductor Corp. puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage.  
Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of nonflammable material or (iii) prevention against any malfunction or mishap.